



# 54AC/74AC112 • 54ACT/74ACT112 Dual JK Negative Edge-Triggered Flip-Flop

## General Description

The 'AC/'ACT112 contain two independent, high-speed JK flip-flops with Direct Set and Clear inputs. Synchronous state changes are initiated by the falling edge of the clock. Triggering occurs at a voltage level of the clock and is not directly related to the transition time. The J and K inputs can change when the clock is in either state without affecting the flip-flop, provided that they are in the desired state during the recommended setup and hold times relative to the falling edge of the clock. A LOW signal on  $\bar{S}_{D1}$  or  $\bar{C}_{D1}$  prevents clocking and forces Q or  $\bar{Q}$  HIGH, respectively. Simultaneous LOW signals on  $\bar{S}_{D1}$  and  $\bar{C}_{D1}$  make both Q and  $\bar{Q}$  HIGH.

Information for 'AC112 and 54 Grade is ADVANCED INFORMATION.

### Asynchronous Inputs:

LOW input to  $\bar{S}_D$  sets Q to HIGH level

LOW input to  $\bar{C}_D$  sets Q to LOW level

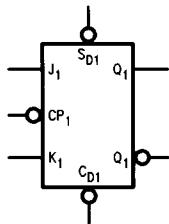
Clear and Set are independent of clock

Simultaneous LOW on  $\bar{C}_D$  and  $\bar{S}_D$  makes both Q and  $\bar{Q}$  HIGH

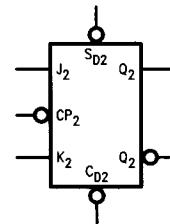
## Features

- 'ACT112 has TTL-compatible inputs
- Outputs source/sink 24 mA

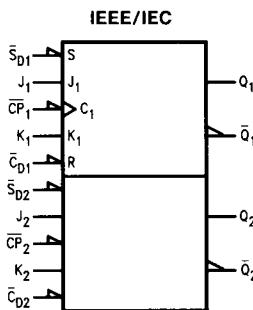
## Logic Symbols



TL/F/9924-1



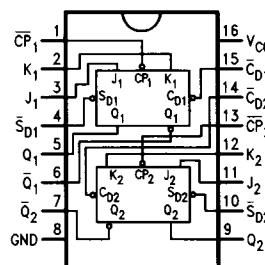
TL/F/9924-2



TL/F/9924-4

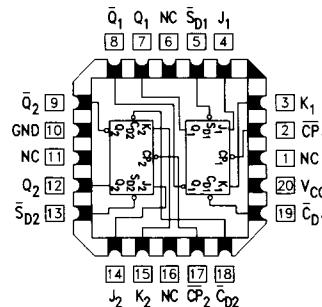
## Connection Diagrams

**Pin Assignment  
for DIP, SOIC and Flatpak**



TL/F/9924-3

**Pin Assignment  
for LCC**



TL/F/9924-5

Pin Names	Description
J <sub>1</sub> , J <sub>2</sub> , K <sub>1</sub> , K <sub>2</sub>	Data Inputs
$\bar{C}P_1$ , $\bar{C}P_2$	Clock Pulse Inputs (Active Falling Edge)
$\bar{C}D_1$ , $\bar{C}D_2$	Direct Clear Inputs (Active LOW)
$\bar{S}D_1$ , $\bar{S}D_2$	Direct Set Inputs (Active LOW)
Q <sub>1</sub> , Q <sub>2</sub> , $\bar{Q}_1$ , $\bar{Q}_2$	Outputs

## Truth Table

Inputs				Outputs		
$\bar{S}_D$	$\bar{C}_D$	$\bar{CP}$	J	K	Q	$\bar{Q}$
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H	H
H	H	$\sim$	h	h	$\bar{Q}_0$	$Q_0$
H	H	$\sim$	l	h	L	H
H	H	$\sim$	h	l	H	L
H	H	$\sim$	l	l	$Q_0$	$\bar{Q}_0$

H (h) = HIGH Voltage Level

L (l) = LOW Voltage Level

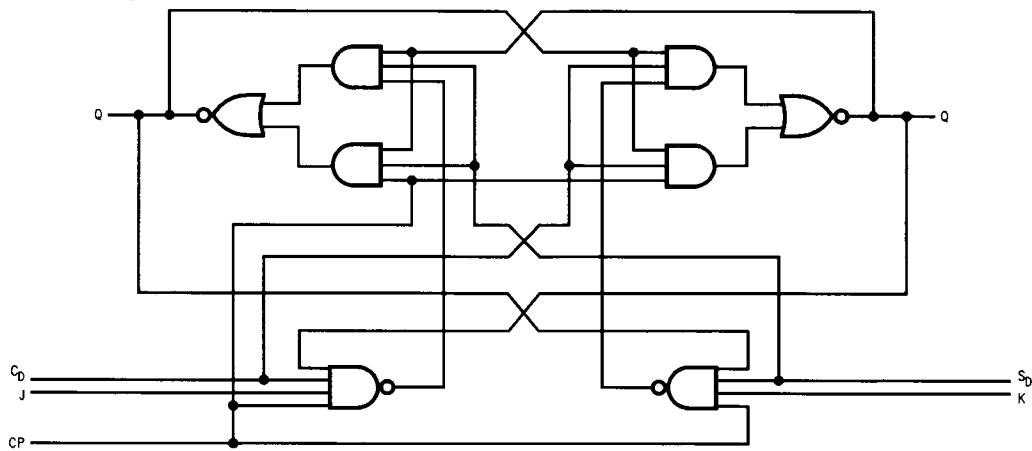
X = Immaterial

$\sim$  = HIGH-to-LOW Clock Transition

$Q_0$  ( $\bar{Q}_0$ ) = Before HIGH-to-LOW Transition of Clock

Lower case letters indicate the state of the referenced input or output one setup time prior to the HIGH-to-LOW clock transition.

## Logic Diagram (One Half Shown)



TL/F/9924-6

## Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V <sub>CC</sub> )	-0.5V to + 7.0V
DC Input Diode Current (I <sub>IK</sub> )	
V <sub>I</sub> = -0.5V	-20 mA
V <sub>I</sub> = V <sub>CC</sub> + 0.5V	+20 mA
DC Input Voltage (V <sub>I</sub> )	-0.5V to V <sub>CC</sub> + 0.5V
DC Output Diode Current (I <sub>OK</sub> )	
V <sub>O</sub> = -0.5V	-20 mA
V <sub>O</sub> = V <sub>CC</sub> + 0.5	+20 mA
DC Output Voltage (V <sub>O</sub> )	-0.5V to V <sub>CC</sub> + 0.5V
DC Output Source or Sink Current (I <sub>O</sub> )	± 50 mA
DC V <sub>CC</sub> or Ground Current per Output Pin (I <sub>CC</sub> or I <sub>GND</sub> )	± 50 mA
Storage Temperature (T <sub>STG</sub> )	-65°C to + 150°C
Junction Temperature (T <sub>J</sub> )	
CDIP	175°C
PDIP	140°C

**Note 1:** Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT™ circuits outside databook specifications.

## Recommended Operating Conditions

Supply Voltage (V <sub>CC</sub> )	2.0V to 6.0V 4.5V to 5.5V
'AC	
'ACT	
Input Voltage (V <sub>I</sub> )	0V to V <sub>CC</sub>
Output Voltage (V <sub>O</sub> )	0V to V <sub>CC</sub>
Operating Temperature (T <sub>A</sub> )	
74AC/ACT	-40°C to + 85°C
54AC/ACT	-55°C to + 125°C
Minimum Input Edge Rate ( $\Delta V/\Delta t$ )	
'AC Devices	
V <sub>IN</sub> from 30% to 70% of V <sub>CC</sub>	
V <sub>CC</sub> @ 3.3V, 4.5V, 5.5V	125 mV/ns
'ACT Devices	
V <sub>IN</sub> from 0.8V to 2.0V	
V <sub>CC</sub> @ 4.5V, 5.5V	125 mV/ns

## DC Characteristics for 'AC Family Devices

Symbol	Parameter	V <sub>CC</sub> (V)	74AC		54AC	74AC	Units	Conditions
			T <sub>A</sub> = + 25°C		T <sub>A</sub> = - 55°C to + 125°C	T <sub>A</sub> = - 40°C to + 85°C		
			Typ	Guaranteed Limits				
V <sub>IH</sub>	Minimum High Level Input Voltage	3.0 4.5 5.5	1.5 2.25 2.75	2.1 3.15 3.85	2.1 3.15 3.85	2.1 3.15 3.85	V	V <sub>OUT</sub> = 0.1V or V <sub>CC</sub> - 0.1V
V <sub>IL</sub>	Maximum Low Level Input Voltage	3.0 4.5 5.5	1.5 2.25 2.75	0.9 1.35 1.65	0.9 1.35 1.65	0.9 1.35 1.65	V	V <sub>OUT</sub> = 0.1V or V <sub>CC</sub> - 0.1V
V <sub>OH</sub>	Minimum High Level Output Voltage	3.0 4.5 5.5	2.99 4.49 5.49	2.9 4.4 5.4	2.9 4.4 5.4	2.9 4.4 5.4	V	I <sub>OUT</sub> = - 50 μA
		3.0 4.5 5.5		2.56 3.86 4.86	2.4 3.7 4.7	2.46 3.76 4.76	V	*V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub> - 12 mA I <sub>OH</sub> - 24 mA - 24 mA
V <sub>OL</sub>	Maximum Low Level Output Voltage	3.0 4.5 5.5	0.002 0.001 0.001	0.1 0.1 0.1	0.1 0.1 0.1	0.1 0.1 0.1	V	I <sub>OUT</sub> = 50 μA
		3.0 4.5 5.5		0.36 0.36 0.36	0.5 0.5 0.5	0.44 0.44 0.44	V	*V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub> 12 mA I <sub>OL</sub> 24 mA 24 mA

\*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

**Note:** I<sub>IN</sub> and I<sub>CC</sub> @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V V<sub>CC</sub>.  
I<sub>CC</sub> for 54AC @ 25°C is identical to 74AC @ 25°C.

## DC Characteristics for 'AC Family Devices (Continued)

Symbol	Parameter	V <sub>CC</sub> (V)	74AC		54AC	74AC	Units	Conditions
			T <sub>A</sub> = + 25°C		T <sub>A</sub> = - 55°C to + 125°C	T <sub>A</sub> = - 40°C to + 85°C		
			Typ	Guaranteed Limits				
I <sub>IN</sub>	Maximum Input Leakage Current	5.5		± 0.1	± 1.0	± 1.0	μA	V <sub>I</sub> = V <sub>CC</sub> , GND
I <sub>OLD</sub>	†Minimum Dynamic Output Current	5.5			50	75	mA	V <sub>OLD</sub> = 1.65V Max
I <sub>OHD</sub>		5.5			-50	-75	mA	V <sub>OHD</sub> = 3.85V Min
I <sub>CC</sub>	Maximum Quiescent Supply Current	5.5		4.0	80.0	40.0	μA	V <sub>IN</sub> = V <sub>CC</sub> or GND

\*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

Note: I<sub>IN</sub> and I<sub>CC</sub> @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V V<sub>CC</sub>.

I<sub>CC</sub> for 54AC @ 25°C is identical to 74AC @ 25°C.

## DC Characteristics for 'ACT Family Devices

Symbol	Parameter	V <sub>CC</sub> (V)	74ACT		54ACT	74ACT	Units	Conditions
			T <sub>A</sub> = + 25°C		T <sub>A</sub> = - 55°C to + 125°C	T <sub>A</sub> = - 40°C to + 85°C		
			Typ	Guaranteed Limits				
V <sub>IH</sub>	Minimum High Level Input Voltage	4.5	1.5	2.0	2.0	2.0	V	V <sub>OUT</sub> = 0.1V or V <sub>CC</sub> - 0.1V
		5.5	1.5	2.0	2.0	2.0		
V <sub>IL</sub>	Maximum Low Level Input Voltage	4.5	1.5	0.8	0.8	0.8	V	V <sub>OUT</sub> = 0.1V or V <sub>CC</sub> - 0.1V
		5.5	1.5	0.8	0.8	0.8		
V <sub>OH</sub>	Minimum High Level Output Voltage	4.5	4.49	4.4	4.4	4.4	V	I <sub>OUT</sub> = - 50 μA
		5.5	5.49	5.4	5.4	5.4		
		4.5		3.86	3.70	3.76	V	*V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub> I <sub>OH</sub> - 24 mA
		5.5		4.86	4.70	4.76		I <sub>OH</sub> - 24 mA
V <sub>OL</sub>	Maximum Low Level Output Voltage	4.5	0.001	0.1	0.1	0.1	V	I <sub>OUT</sub> = 50 μA
		5.5	0.001	0.1	0.1	0.1		
		4.5		0.36	0.50	0.44	V	*V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub> I <sub>OL</sub> 24 mA
		5.5		0.36	0.50	0.44		24 mA
I <sub>IN</sub>	Maximum Input Leakage Current	5.5		± 0.1	± 1.0	± 1.0	μA	V <sub>I</sub> = V <sub>CC</sub> , GND
I <sub>CCT</sub>	Maximum I <sub>CC</sub> /Input	5.5	0.6		1.6	1.5	mA	V <sub>I</sub> = V <sub>CC</sub> - 2.1V
I <sub>OLD</sub>	†Minimum Dynamic Output Current	5.5			50	75	mA	V <sub>OLD</sub> = 1.65V Max
I <sub>OHD</sub>		5.5			-50	-75	mA	V <sub>OHD</sub> = 3.85V Min
I <sub>CC</sub>	Maximum Quiescent Supply Current	5.5		4.0	80.0	40.0	μA	V <sub>IN</sub> = V <sub>CC</sub> or GND

\*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

Note: I<sub>CC</sub> for 54ACT @ 25°C is identical to 74ACT @ 25°C.

## AC Electrical Characteristics:

Symbol	Parameter	V <sub>CC</sub> * (V)	74AC			54AC		74AC		Units	
			T <sub>A</sub> = + 25°C C <sub>L</sub> = 50 pF			T <sub>A</sub> = - 55°C to + 125°C C <sub>L</sub> = 50 pF		T <sub>A</sub> = - 40°C to + 85°C C <sub>L</sub> = 50 pF			
			Min	Typ	Max	Min	Max	Min	Max		
f <sub>max</sub>	Maximum Clock Frequency	3.3 5.0	125 150					100 125		MHz	
t <sub>PLH</sub>	Propagation Delay CP <sub>n</sub> to Q <sub>n</sub> or $\bar{Q}_n$	3.3 5.0	1.0 1.0	11.0 8.5	14.0 11.0			1.0 1.0	15.0 12.0	ns	
t <sub>PHL</sub>	Propagation Delay CP <sub>n</sub> to Q <sub>n</sub> or $\bar{Q}_n$	3.3 5.0	1.0 1.0	11.0 8.5	14.0 11.0			1.0 1.0	15.0 12.0	ns	
t <sub>PLH</sub>	Propagation Delay $\bar{C}_{Dn}$ or $\bar{S}_{Dn}$ to Q <sub>n</sub> or $\bar{Q}_n$	3.3 5.0	1.0 1.0	9.5 7.0	12.5 9.5			1.0 1.0	13.5 10.5	ns	
t <sub>PHL</sub>	Propagation Delay $\bar{C}_{Dn}$ or $\bar{S}_{Dn}$ to Q <sub>n</sub> or $\bar{Q}_n$	3.3 5.0	1.0 1.0	11.5 9.0	14.5 11.0			1.0 1.0	15.5 12.5	ns	

\*Voltage Range 3.3 is 3.3V  $\pm$  0.3V

Voltage Range 5.0 is 5.0V  $\pm$  0.5V

## AC Operating Requirements:

Symbol	Parameter	V <sub>CC</sub> * (V)	74AC		54AC	74AC		Units	
			T <sub>A</sub> = + 25°C C <sub>L</sub> = 50 pF		T <sub>A</sub> = - 55°C to + 125°C C <sub>L</sub> = 50 pF	T <sub>A</sub> = - 40°C to + 85°C C <sub>L</sub> = 50 pF			
			Typ	Guaranteed Minimum					
t <sub>s</sub>	Setup Time, HIGH or LOW J <sub>n</sub> or $\bar{K}_n$ to CP <sub>n</sub>	3.3 5.0	3.0 2.0	5.5 4.5			6.0 4.6	ns	
t <sub>h</sub>	Hold Time, HIGH or LOW J <sub>n</sub> or $\bar{K}_n$ to CP <sub>n</sub>	3.3 5.0	-1.5 -0.5	0 0			0 0	ns	
t <sub>w</sub>	Pulse Width $\bar{C}_{Dn}$ or $\bar{S}_{Dn}$	3.3 5.0	2.0 2.0	5.5 4.5			7.0 5.0	ns	
t <sub>rec</sub>	Recovery Time $\bar{C}_{Dn}$ or $\bar{S}_{Dn}$ to CP <sub>n</sub>	3.3 5.0	-1.0 -1.0	3.5 3.0			3.5 3.0	ns	

\*Voltage Range 3.3 is 3.3V  $\pm$  0.3V

Voltage Range 5.0 is 5.0V  $\pm$  0.5V

## AC Electrical Characteristics:

Symbol	Parameter	V <sub>CC</sub> * (V)	74ACT			54ACT		74ACT		Units	
			T <sub>A</sub> = + 25°C C <sub>L</sub> = 50 pF			T <sub>A</sub> = - 55°C to + 125°C C <sub>L</sub> = 50 pF		T <sub>A</sub> = - 40°C to + 85°C C <sub>L</sub> = 50 pF			
			Min	Typ	Max	Min	Max	Min	Max		
f <sub>max</sub>	Maximum Clock Frequency	5.0	100					80		MHz	
t <sub>PLH</sub>	Propagation Delay CP <sub>n</sub> to Q <sub>n</sub> or $\bar{Q}_n$	5.0	1.0	9.5	13.0			1.0	14.0	ns	
t <sub>PHL</sub>	Propagation Delay CP <sub>n</sub> to Q <sub>n</sub> or $\bar{Q}_n$	5.0	1.0	9.5	13.0			1.0	14.0	ns	
t <sub>PLH</sub>	Propagation Delay $\bar{C}_{Dn}$ or $\bar{S}_{Dn}$ to Q <sub>n</sub> or $\bar{Q}_n$	5.0	1.0	7.0	10.0			1.0	11.0	ns	
t <sub>PHL</sub>	Propagation Delay $\bar{C}_{Dn}$ or $\bar{S}_{Dn}$ to Q <sub>n</sub> or $\bar{Q}_n$	5.0	1.0	9.5	12.5			1.0	13.5	ns	

Voltage Range 5.0 is 5.0V ± 0.5V

## AC Operating Requirements:

Symbol	Parameter	V <sub>CC</sub> * (V)	74ACT			54ACT		74ACT		Units	
			T <sub>A</sub> = + 25°C C <sub>L</sub> = 50 pF			T <sub>A</sub> = - 55°C to + 125°C C <sub>L</sub> = 50 pF		T <sub>A</sub> = - 40°C to + 85°C C <sub>L</sub> = 50 pF			
			Typ	Guaranteed Minimum							
t <sub>s</sub>	Setup Time, HIGH or LOW J <sub>n</sub> or $\bar{K}_n$ to CP <sub>n</sub>	5.0	2.5	7.0				8.0		ns	
t <sub>h</sub>	Hold Time, HIGH or LOW J <sub>n</sub> or $\bar{K}_n$ to CP <sub>n</sub>	5.0	0.5	1.5				1.5		ns	
t <sub>w</sub>	Pulse Width CP <sub>n</sub> or $\bar{C}_{Dn}$ or $\bar{S}_{Dn}$	5.0	4.0	7.0				8.0		ns	
t <sub>rec</sub>	Recovery Time $\bar{C}_{Dn}$ or $\bar{S}_{Dn}$ to CP <sub>n</sub>	5.0	1.0	3.0				3.0		ns	

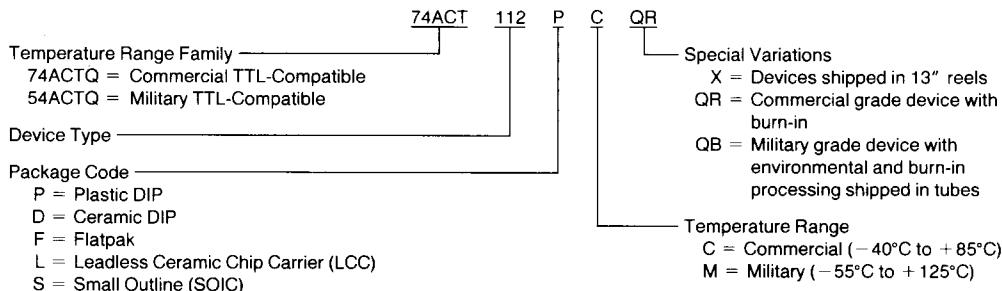
Voltage Range 5.0 is 5.0V ± 0.5V

## Capacitance

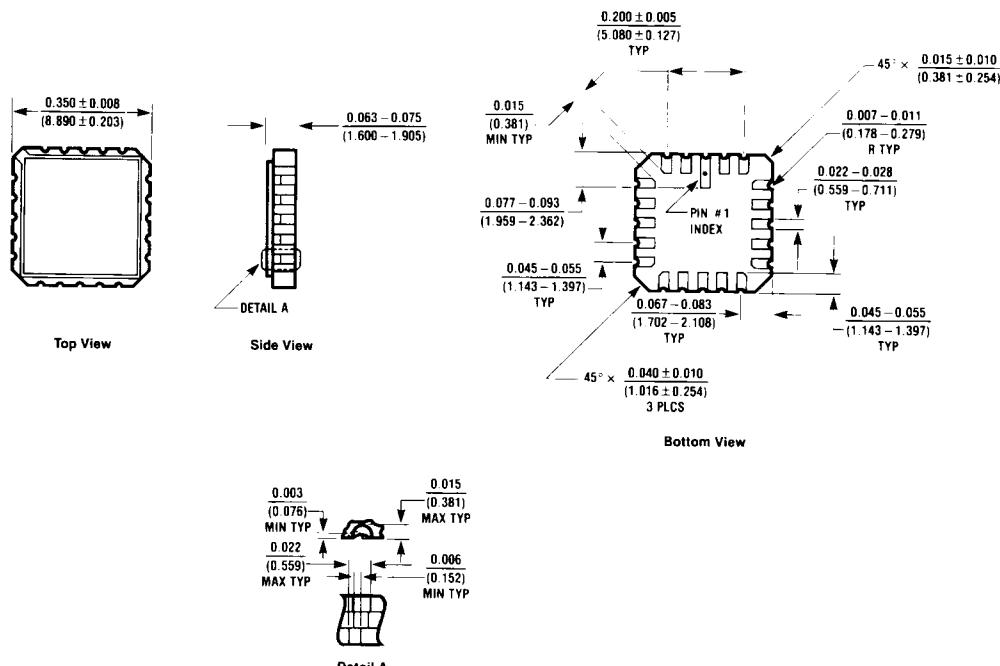
Symbol	Parameter	Typ	Units	Conditions
C <sub>IN</sub>	Input Capacitance	4.5	pF	V <sub>CC</sub> = 5.0V
C <sub>PD</sub>	Power Dissipation Capacitance	35	pF	V <sub>CC</sub> = 5.0V

## Ordering Information

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:



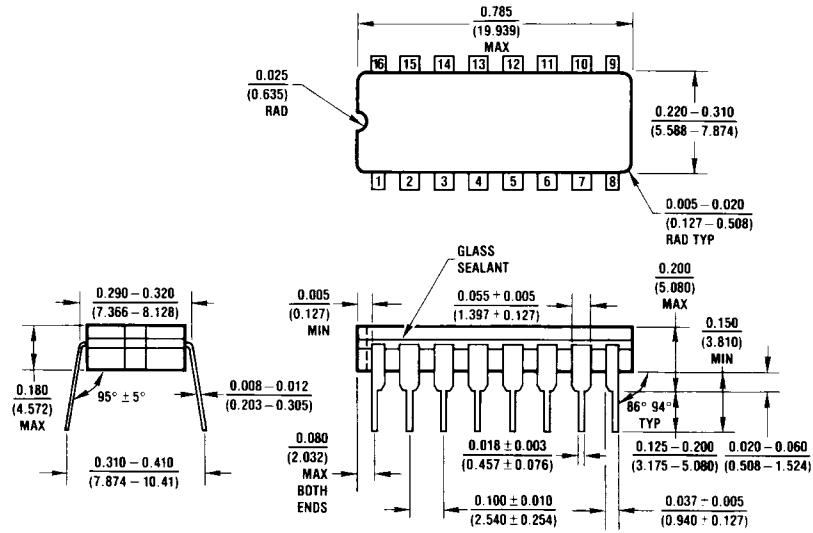
## Physical Dimensions inches (millimeters)



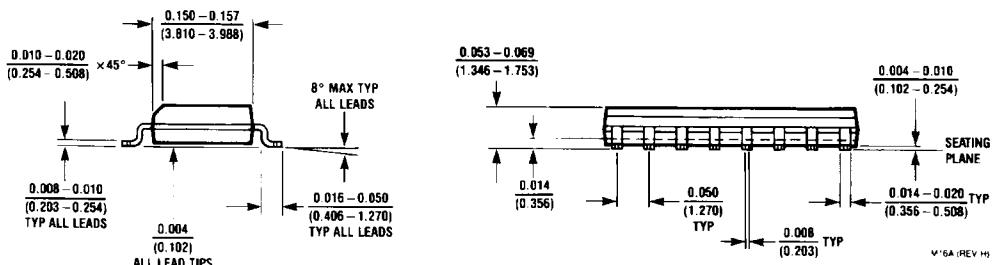
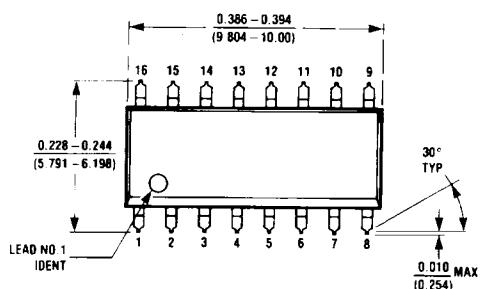
20-Lead Ceramic Leadless Chip Carrier (L)  
NS Package Number E20A

L20A REV. D

## Physical Dimensions inches (millimeters) (Continued)

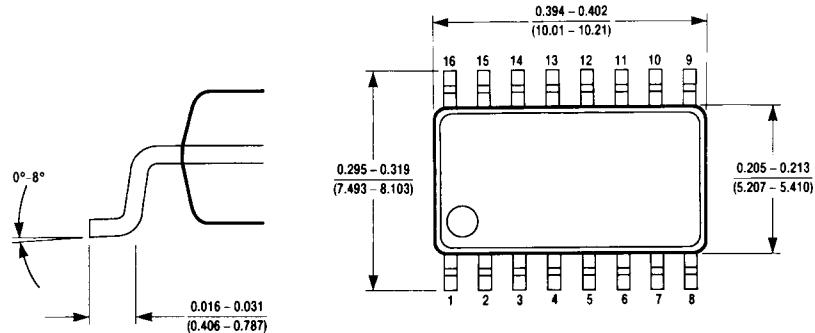


16-Lead Ceramic Dual-In-Line Package (D)  
NS Package Number J16A

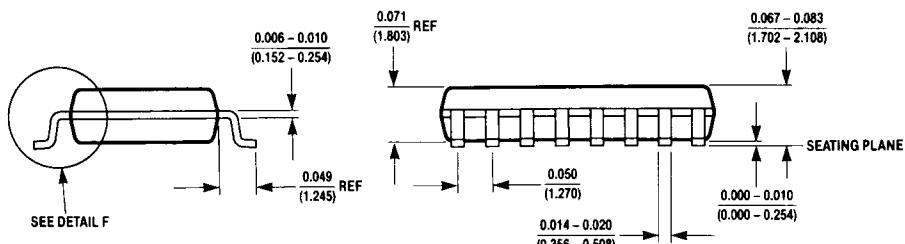


16-Lead Small Outline Integrated Circuit (S)  
NS Package Number M16A

## Physical Dimensions inches (millimeters) (Continued)



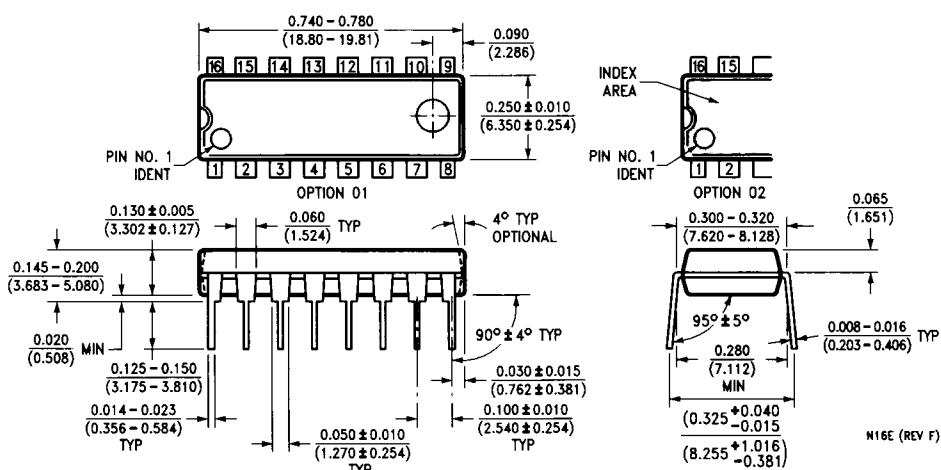
DETAIL F



SEE DETAIL F

M16D (REV A)

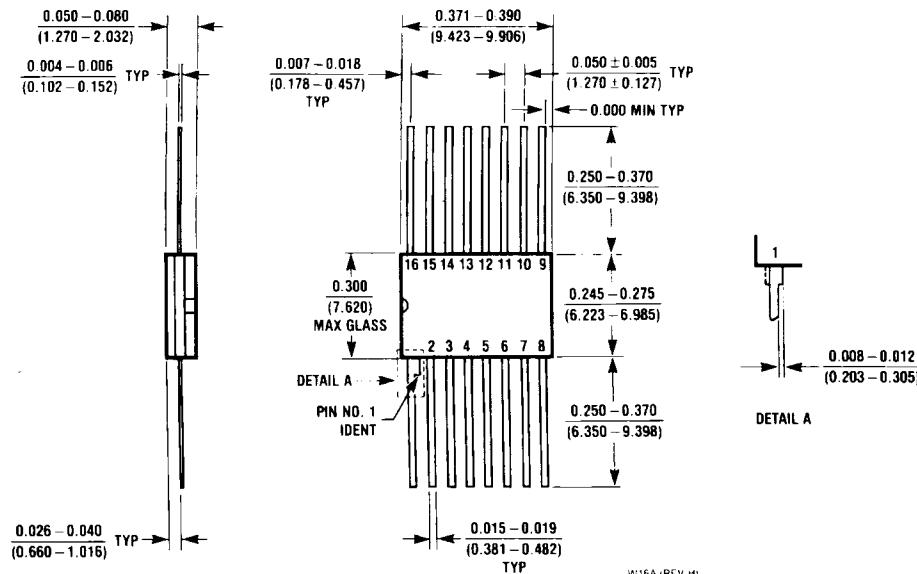
**16-Lead Small Outlined Package—EIAJ (SJ)  
NS Package Number M16D**



**16-Lead Plastic Dual-In-Line Package (P)  
NS Package Number N16E**

**Physical Dimensions** inches (millimeters) (Continued)

Lit #: 114600



**16-Lead Ceramic Flatpak (F)  
NS Package Number W16A**

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



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